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Form PTO-1449 US Dept. of Commerc (REV. 8-83) PATENT & TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT			ATTY DOCKET NO. 040852.98			APPLICATION NO. Rule 59(b) Divisional of Application No. 10/263,070		
(Use several sheets if necessary)		1	APPLICA Satoshi I	ANT(S) NOUE; Tatsuya SHIMODA				
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<u> </u>	U.S	. PATI	ENT DOCU	JMENTS				
EXAMINER INITIAL	DOCUMENT NUMBER	1	DATE	NAME		CLASS	SUB CLASS	
JED	5,747,121	05/1	1998	Okazaki et al.				
	5,767,930	06/1	1998	Kobayashi et al.				
	5,807,772	09/1	1998	Takemura				
	5,888,839	03/1	1999	ino et al.				
	5,468,521	11/1	1995	Kanai et al.				
	5,008,218	04/1	1991	Kawachi et al.				
	5,693,541	12/1	1997	Yamazaki et al.				
	5,589,962	12/1	1996	Yamamoto et al.				
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16/19	5,926,735		1999	Yamazaki et al.				
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	DOCUMENT NUMBER	Į, I	DATE	COUNTRY		CLASS	SUB CLASS	
16	JP-A-6-291291	10/1	994	JAPAN				
	JP-A-8-288522	11/1	996	JAPAN				
	JP-A-61-231714	10/1	986	JAPAN				
	JP-A-8-62591	03/1	996	JAPAN				
NO 1	WO 98/09333	03/1	998	WIPO				
,	OTHER DOCUMENTS (In	cluding	g Author, T	itle, Date, Pertinent Pages, etc.)		<u> </u>		
NB	Sameshima, T. "Laser Beam Application				<u>96-98</u> , (1996), pp. 3	52-358.	
								
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Date: December 31, 2003

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Form PTO-14 (REV. 1/06)	449	US Dept. of Commerce PATENT & TRADEMARK OFFICE	ATTY 1 040852	DOCKET NO. .98	APPLICATION NO. 10/748,206				
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100	1.	Sameshima T., Laser beam application to the thin film transistors, Applied Surface Science, April 2, 1996 Vol. 96-							
1111		Pages 352-358		· · · · · · · · · · · · · · · · · · ·					
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	2.	WO 93/16491	08/19/19	93	WIPO					
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26	1	JP07-098460A w/machine translation)	04/1995		Japan				
	2	JP08-250745A (w/machine translation)	09/1996		Japan				-
	3	JP08-262474A (w/machine translation)	10/1996		Japan				
	4	JP08-262475A (w/machine translation)	10/1996		Japan				
	5	JP08-234796A (w/machine translation)	09/1996		Japan				
	6	JP08-278519A (w/machine translation)	10/1	1996	Japan				
	7	JP05-218365A (w/machine translation)	08/1	1993	Japan		_		
	8	JP08-240814A (w/machine translation)	09/1	1996	Japan	-			
	9	JP06-202160A (w/machine translation)	07/1	1994	Japan	· · · · · · · · · · · · · · · · · · ·			. =
		JP63-101830A (w/Abstract)	05/1	988	Japan				
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169	1	WO 92/12453	07/2	23/1992	WIPO						
<u> </u>	2	JP-A-06-504139	05/1	2/1994	JAPAN						
	3	JP-A-06-219052 (w/English- language Abstract & Translation)	08/0)9/1994	JAPAN						
NA	4	JP-A-06-118441 (w/English- language Abstract & Translation)	04/2	28/1994	JAPAN						
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